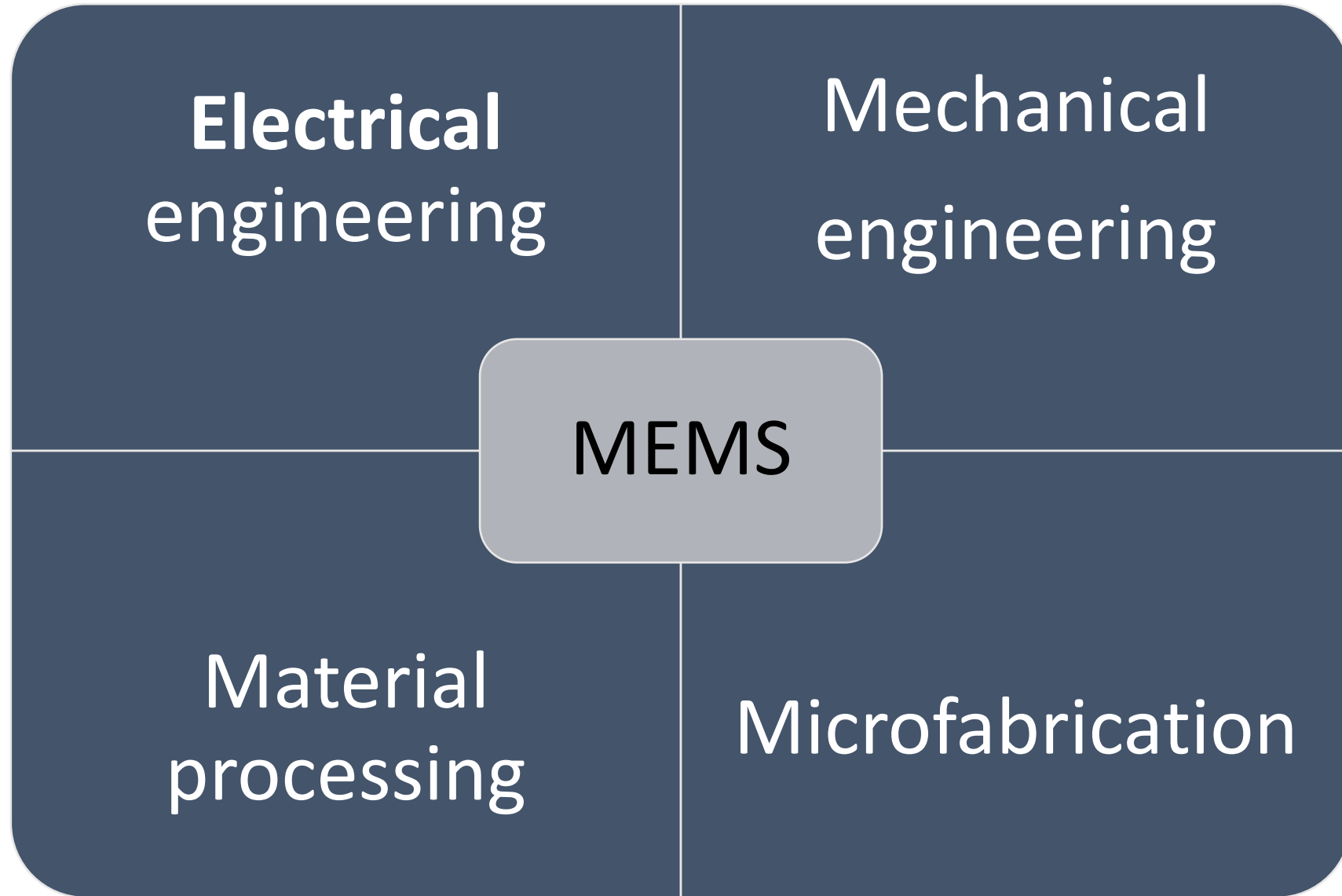
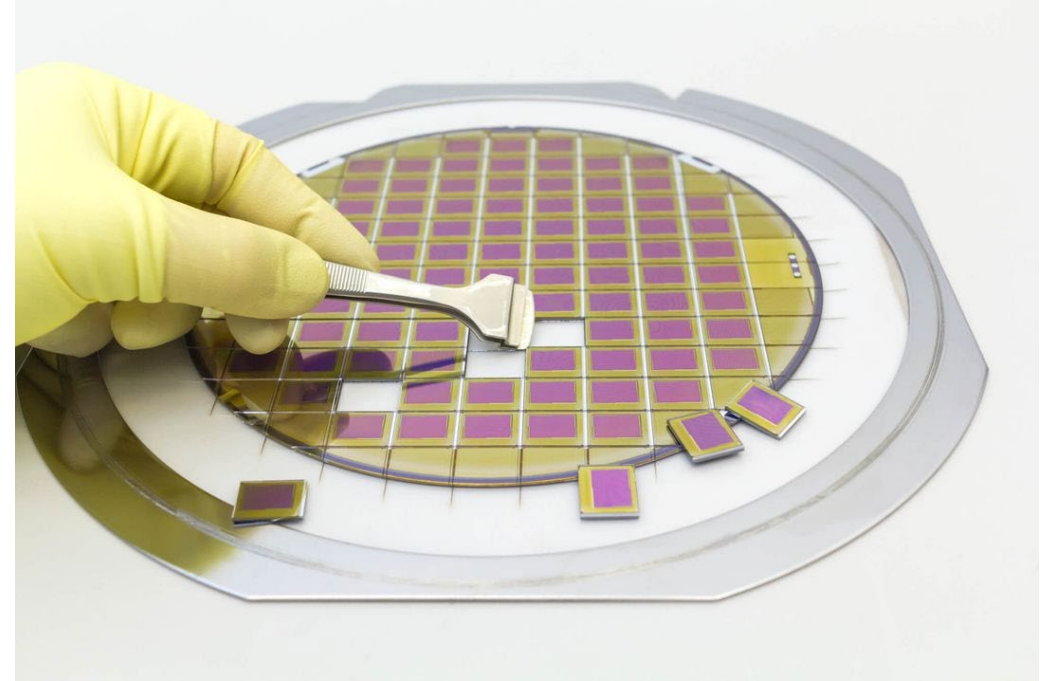
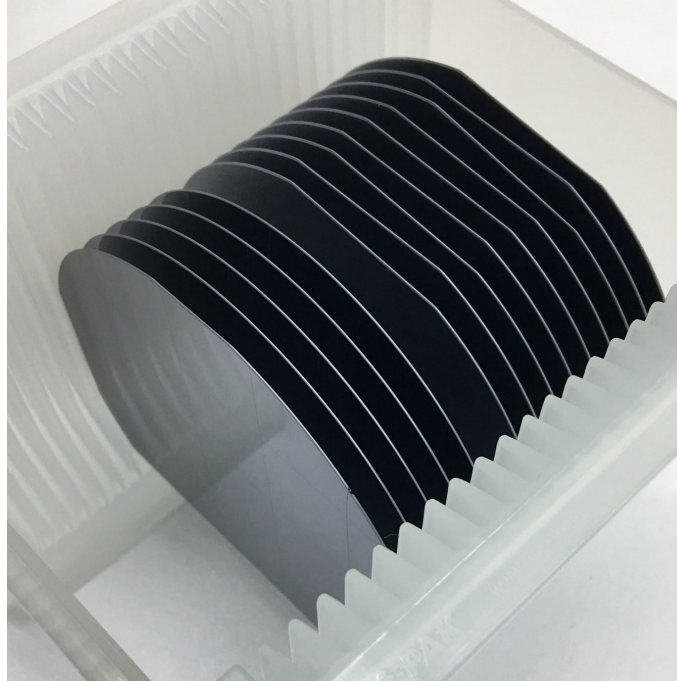


# Review of Essential Basics

Electrical



# Silicon as the substrate



Silicon ingots made by [Czochralski method](#)

<https://www.plutosemi.net/show-14-415-1.html>

<https://www.vritratech.com/store/product/p-type-silicon-wafer-3-inch/>

<https://www.waferworld.com/post/top-causes-of-silicon-wafer-breakage>

<https://www.youtube.com/watch?v=aCOyq4YzBtY>

(Sand to Silicon - The Making of a Chip | Intel)

# Demo of silicon wafer and microheater array

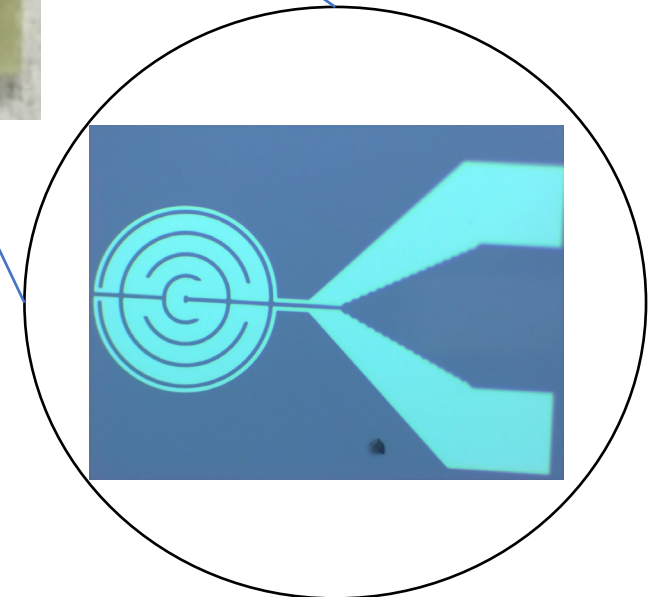
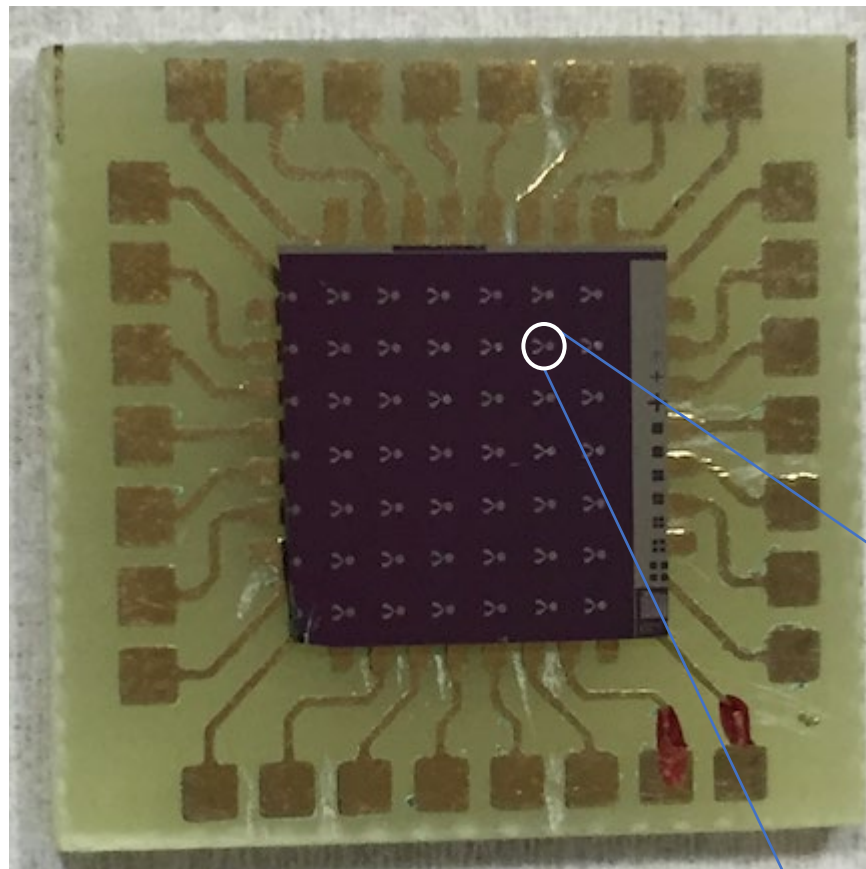
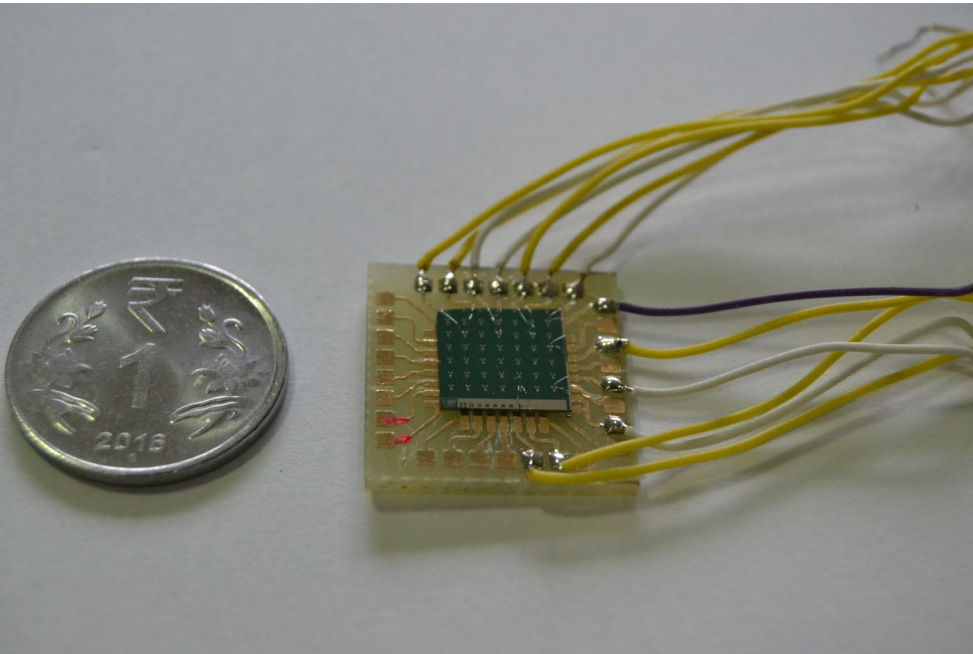


Image © Amruta R Behera

# Czochralski process

- Process brief:

<https://www.youtube.com/watch?v=skRmyhSOu28>

<https://www.youtube.com/watch?v=2qLI-NYdLy8>

- Actual footage of fabrication:

<https://www.youtube.com/watch?v=jh2z-g7GJxE> (video at 2000X)

<https://www.youtube.com/watch?v=XbBc4ByimY8>

- Ingot footage: <https://www.youtube.com/watch?v=O2jrjiRe8cE>
- Shipping wafers: <https://www.youtube.com/watch?v=bB5iWzsztcd>
- Attempt by Adani: <https://www.pv-magazine.com/2022/12/09/adani-unveils-indias-first-silicon-ingot/>

# Conductivity of a semiconductor

Semiconductors  
allow controlling  
of their  
conductivity by

intentionally introduced impurities

externally applied electric field

charge injection

ambient light

temperature variations

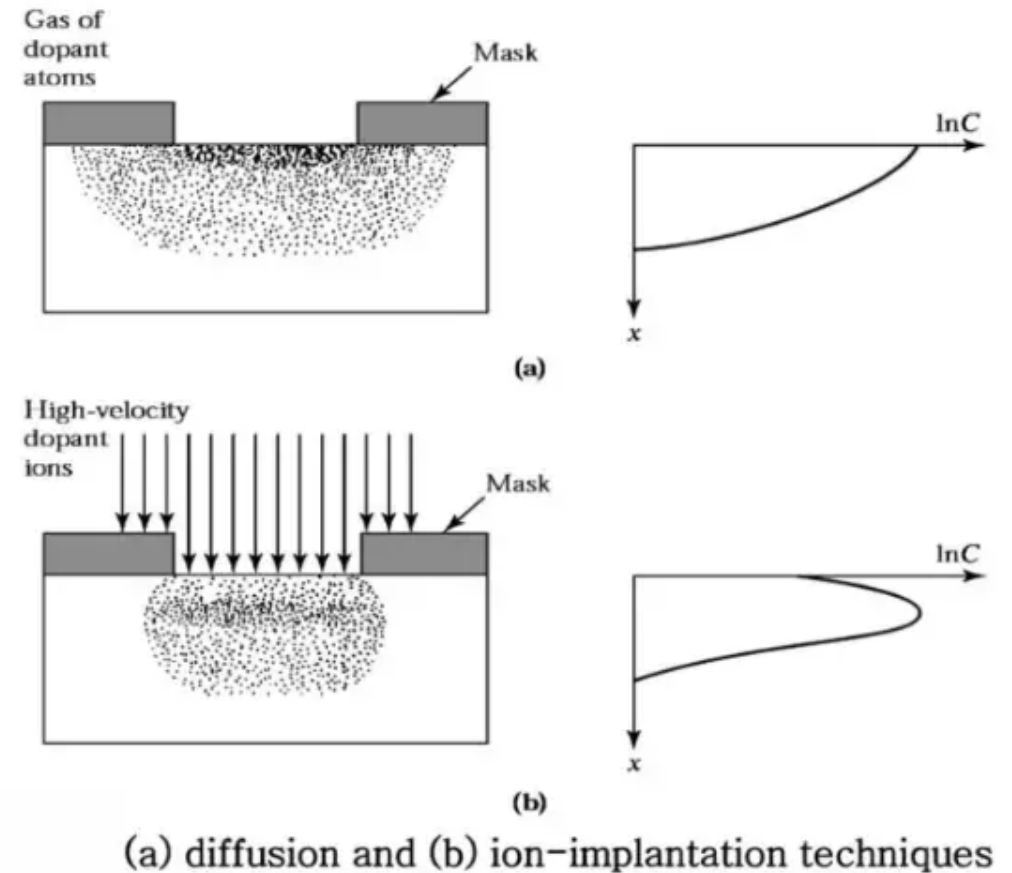


VectorStock® VectorStock.com/11194390

Bandgap = 1.11eV

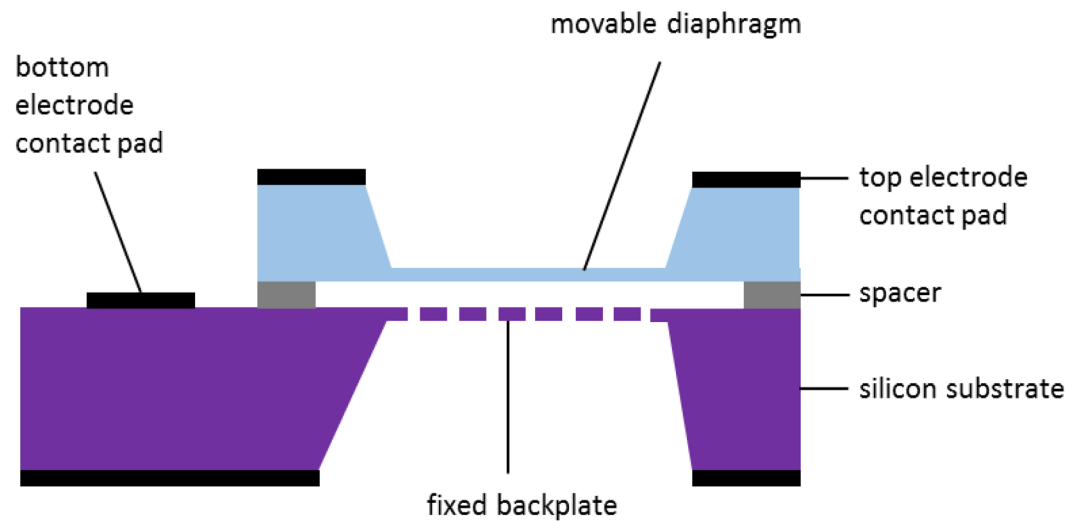
# Doping methods

Silicon as a conductor: electrode, heating element

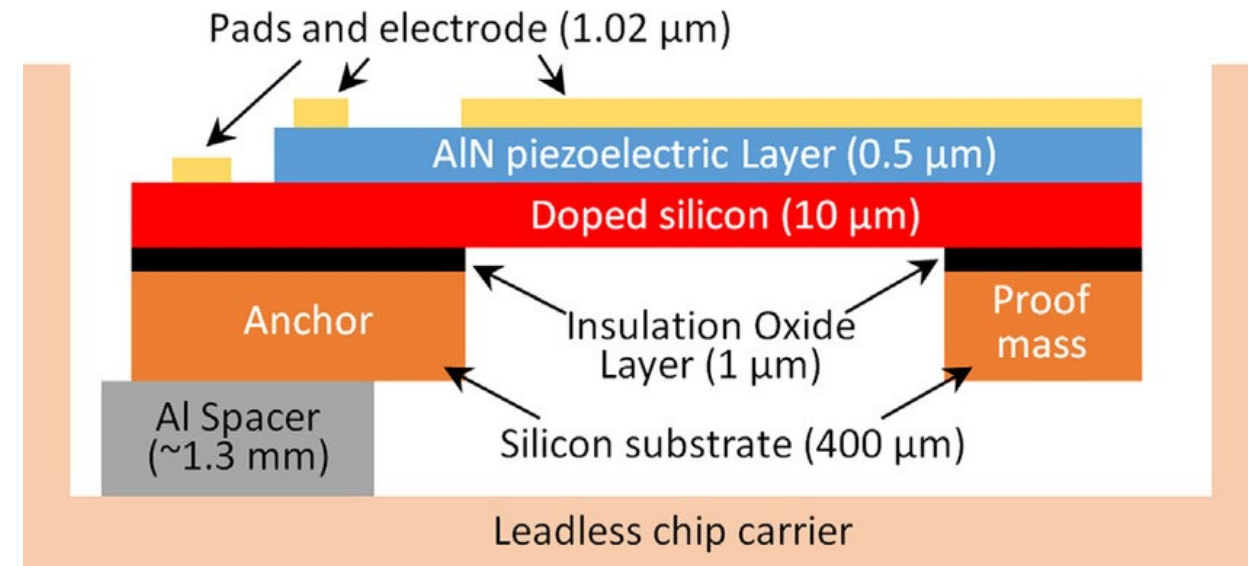




# Use of doped Silicon as electrode in MEMS



Basic structure of a micro-electro-mechanical system (MEMS) capacitive microphone.



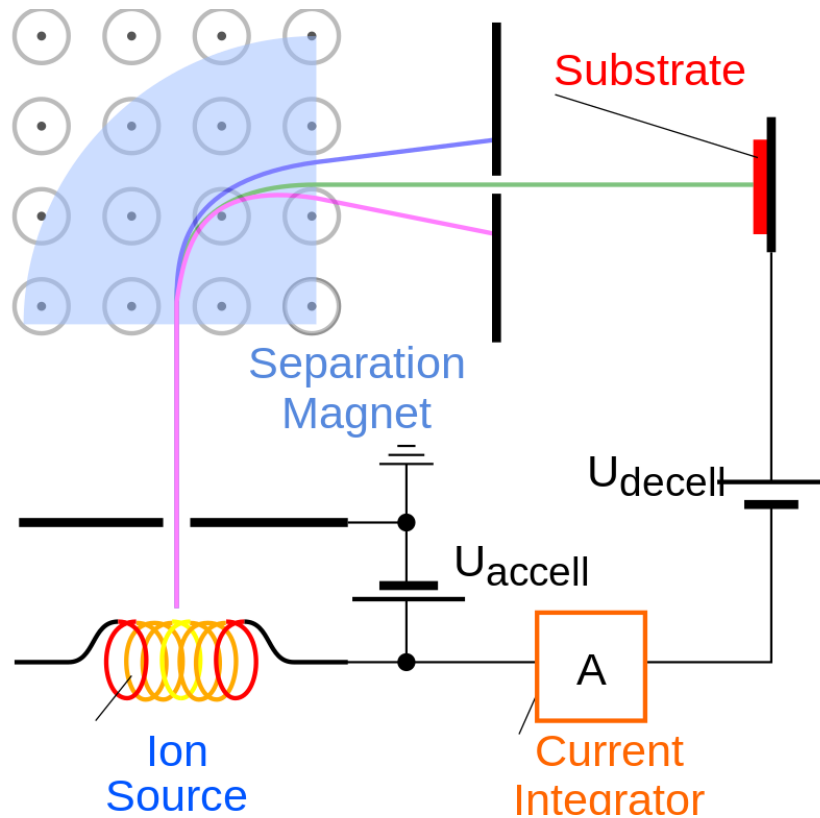
A piezoelectric vibration energy harvester

<https://www.mdpi.com/2072-666X/11/5/484>

[https://www.researchgate.net/figure/MEMS-device-fabrication-process\\_fig6\\_318552423](https://www.researchgate.net/figure/MEMS-device-fabrication-process_fig6_318552423)



# Ion implanter



[https://en.wikipedia.org/wiki/Ion\\_implantation#/media/File:Ion\\_implanter\\_schematic.svg](https://en.wikipedia.org/wiki/Ion_implantation#/media/File:Ion_implanter_schematic.svg)

<https://www.appliedmaterials.com/us/en/semiconductor/products/processes/implant.html>

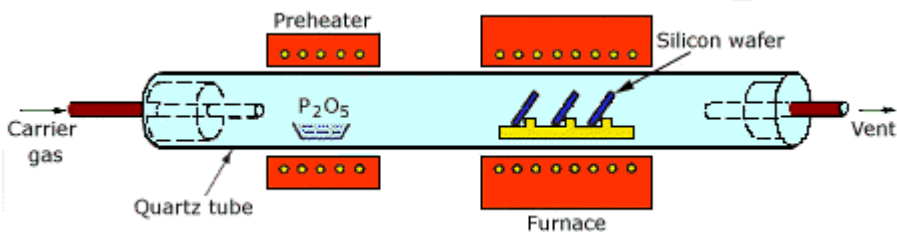
<https://www.appliedmaterials.com/us/en/semiconductor/products/processes/implant/vista-3000xp.html>

Dr. Amruta R. Behere | Palksha University

# Furnace for diffusion doping

Oxidation furnace – similar furnace used for doping  
<https://www.youtube.com/watch?v=Hi-1zN1RVqc>

Phosphorous diffusion  
<https://www.youtube.com/watch?v=3MkiUHZsWro>



# Calculation of charge carrier concentration

$$n = p \equiv n_i.$$

$$n_i^2 = 4 \left( \frac{4\pi^2 m_n^* m_p^* k^2 T^2}{h^2} \right)^{3/2} e^{\frac{-E_g}{kT}},$$

Commonly accepted values of  $n_i$  at  $T = 300^\circ\text{K}$

Silicon	$1.5 \times 10^{10} \text{ cm}^{-3}$
Gallium arsenide	$1.8 \times 10^6 \text{ cm}^{-3}$
Germanium	$2.4 \times 10^{13} \text{ cm}^{-3}$

Law of mass action  $n_0 p_0 = n_i^2.$

$$p_0 + N_d^+ = n_0 + N_a^-.$$

$$n_0 - \frac{n_i^2}{n_0} = N_d^+ - N_a^-$$

$$ax^2 + bx + c = 0$$

$$\frac{-b \pm \sqrt{b^2 - 4ac}}{2a}$$

For  $b^2 \gg c$

$$n_0 = N_d^+ - N_a^-.$$

$$p_0 = N_a^- - N_d^+$$

$$n_0^2 - (N_d^+ - N_a^-)n_0 - n_i^2 = 0.$$

Diagram illustrating the coefficients of the quadratic equation  $n_0^2 - (N_d^+ - N_a^-)n_0 - n_i^2 = 0$ :

- $a=1$  (coefficient of  $n_0^2$ )
- $b$  (coefficient of  $n_0$ , where  $b = -(N_d^+ - N_a^-)$ )
- $c$  (constant term, where  $c = -n_i^2$ )

$$p_0^2 - (N_a^- - N_d^+)p_0 - n_i^2 = 0.$$

# Example 1

Consider a piece of silicon under room temperature and thermal equilibrium. The silicon is doped with boron with a doping concentration of  $10^{16}$  atoms/cm<sup>3</sup>. Find the electron and hole concentrations.

Number of electrons in intrinsic silicon  $1.5 \times 10^{10}$ /cm<sup>3</sup>.

Silicon atom density  $5 \times 10^{22}$ /cm<sup>3</sup>.

## Observations

- The concentration of dopants is much smaller compared to the density of lattice atoms.
- The thermal-equilibrium majority and minority carrier concentrations can differ by many orders of magnitude.



## Example 2

Determine the thermal equilibrium electron and hole concentrations for a given doping concentration.

Consider an germanium sample at  $T = 300^\circ\text{K}$  in which  $N_d = 5 \times 10^{13} \text{ cm}^{-3}$  and  $N_a = 0$ . Assume that  $n_i = 2.4 \times 10^{13} \text{ cm}^{-3}$ .